# TEST REPORT
# FOR
# IEC 61643-1 (7.5.3)
# (SURGE IMMUNITY TEST)

**Report No.: 11-01-MAS-055-01**

| | |
|---|---|
| Client: | JD Auspice Co., Ltd. |
| Product: | Surge Protectetive Device |
| Model No.: | D3-60/***-4MV-R |
| Comment Issues: | N/A |
| Manufacturer/supplier: | JD Auspice Co., Ltd. |
| Serial Voltage | 75 / 150 / 175 / 275 / 300 / 320 / 385 / 440 / 550 / 600 |

| | |
|---|---|
| Date test item received: | 2011/01/07 |
| Date test campaign completed: | 2011/02/09 |
| Date of issue | 2011/02/09 |



*Total number of pages of this test report: 10 pages*

| Test Engineer | Checked By |
|---|---|
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Laboratory Introduction: Electronics Testing Center, Taiwan is recognized, filed and mutual recognition arrangement as following:

1. ISO9001: TüV Product Service
2. ISO/IEC 17025: BSMI, CNLA, DGT, NVLAP, CCIBLAC, UL, Compliance
3. Filing: FCC, Industry Canada, VCCI
4. MRA: Australia, Hong Kong, New Zealand, Singapore, USA, Japan, Korea, China, APLAC through CNLA
5. FCC Registration Number: 90588, 91094, 91095

# SURGE IMMUNITY TEST

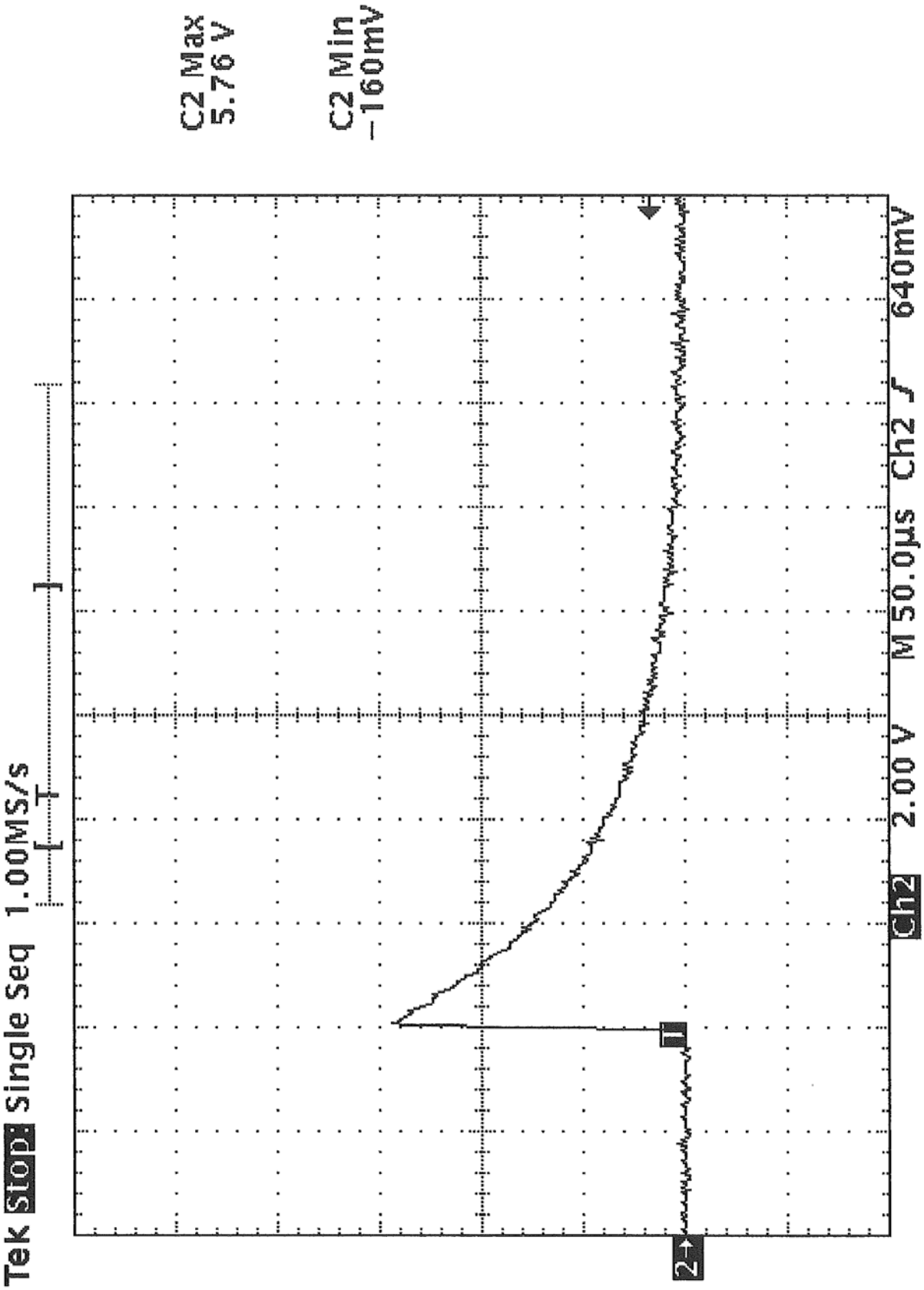
Test Date: Jan. 21, 2011

| | | |
|---|---|---|
| Test Specification | IEC61643-1 (7.5.3) | |
| Test Equipment | | |
| Lightning Surge Simulator \ Noiseken \ LSS-15AX<br>Voltage Probe \ Tektronix \ P6015A<br>Oscilloscope \ Tektronix \ TDS784A | | |
| Climatic Condition | Ambient Temperature: 15 ºC | Relative Humidity: 65 %RH |
| | Atmospheric Pressure: 993 mbar | |
| Test Set-up | Table-top Equipment | |
| Operating Conditions of The Device | Static Mode | |

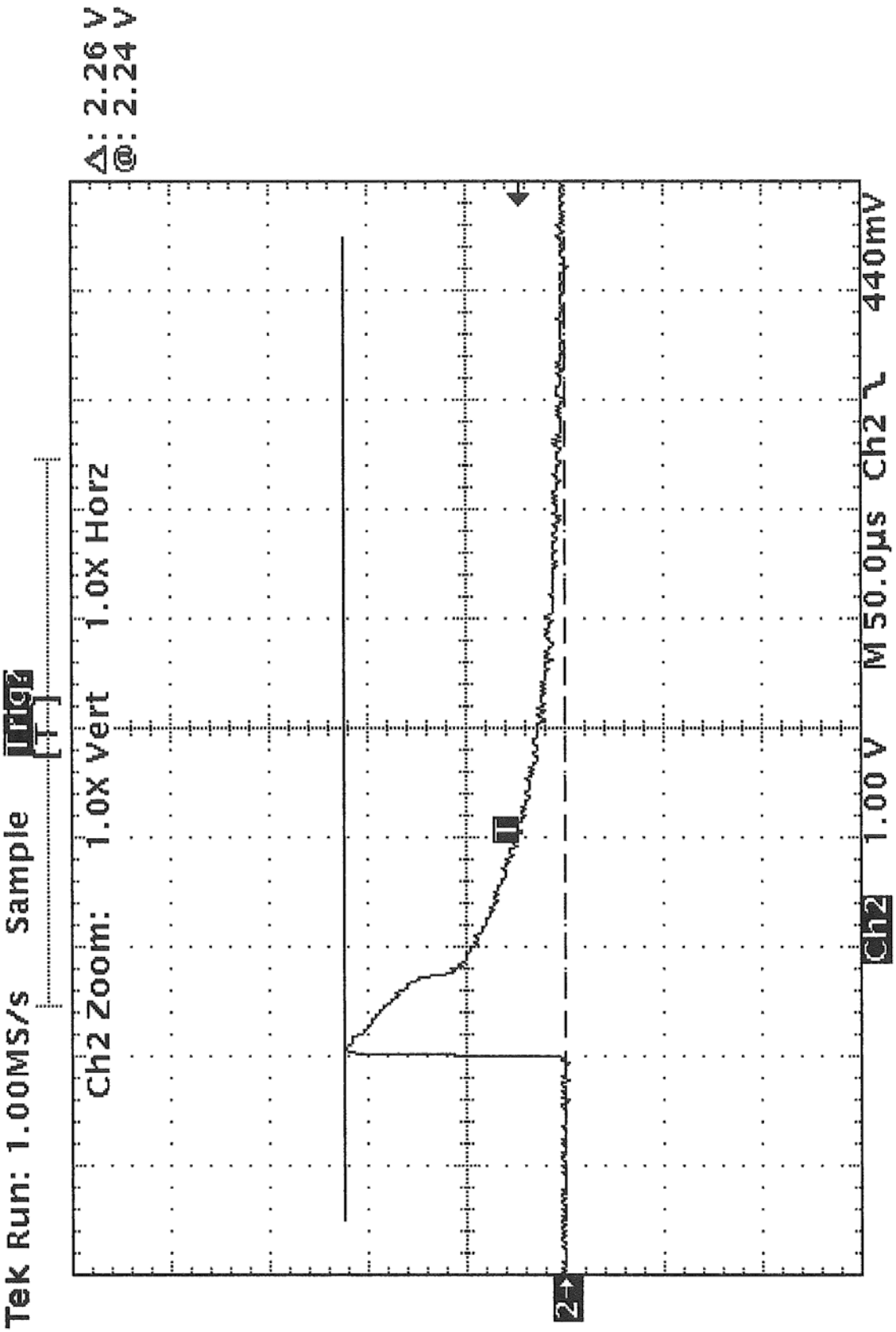
| Waveform: 1.2/50 μs(8/20 μs) | | Repetition rate: 60 sec | Times: 5 times/each condition |
|---|---|---|---|
| \Mode<br>\Voltage \Polarity \Result | | Surge HOT: Device Input | Surge COM: Device Output |
| 6.0 kV | + | A | |
| | - | A | |
| 0.9kV ~ 15.0 kV<br>Step:10% increase | + | A | |
| | - | A | |

Note: " A " means the EUT function was correct during the test.

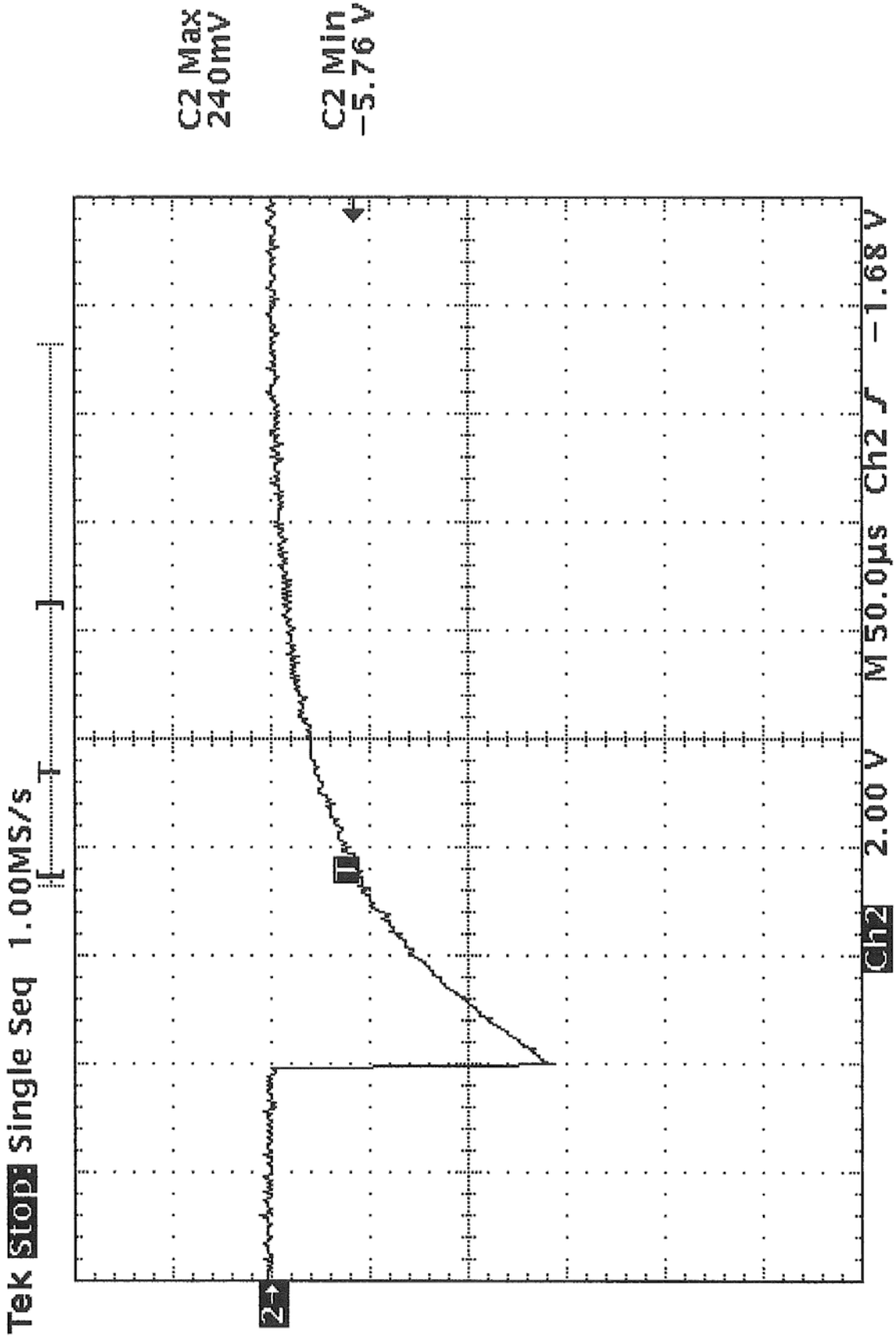
**Test Voltage: +6kV Waveform (Normal)**



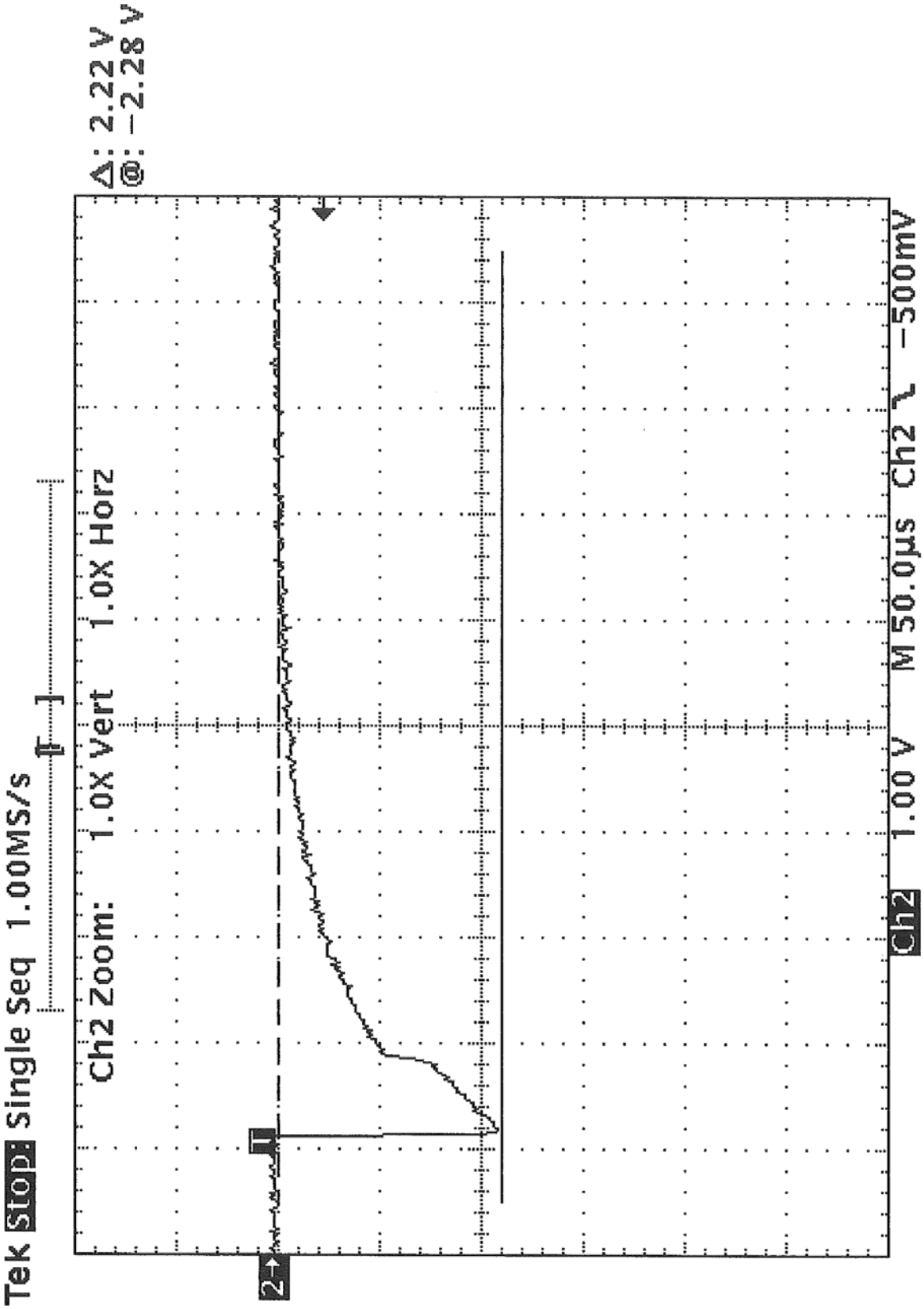
**Test Voltage: +6kV (Device Parallel)**



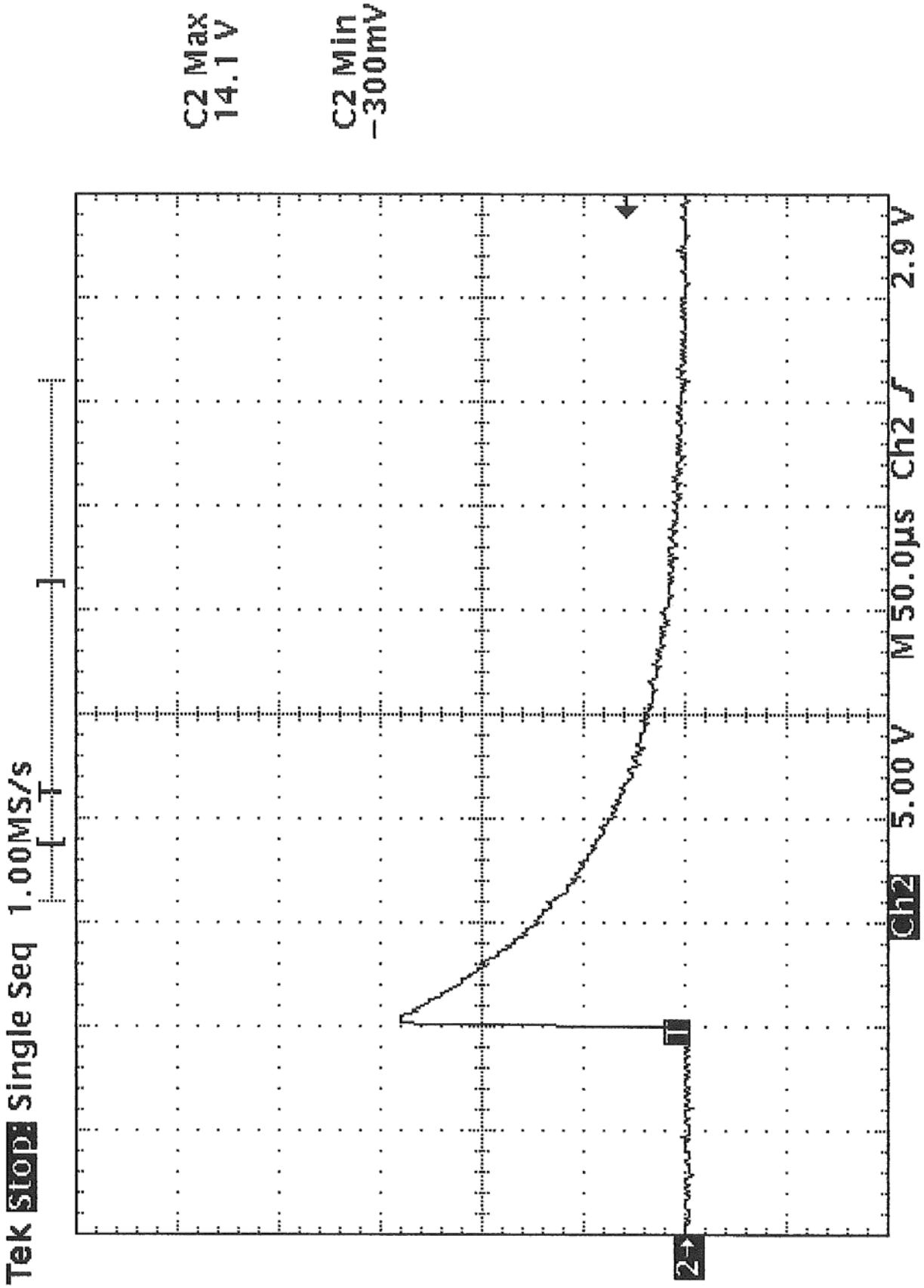
**Test Voltage: -6kV Waveform (Normal)**



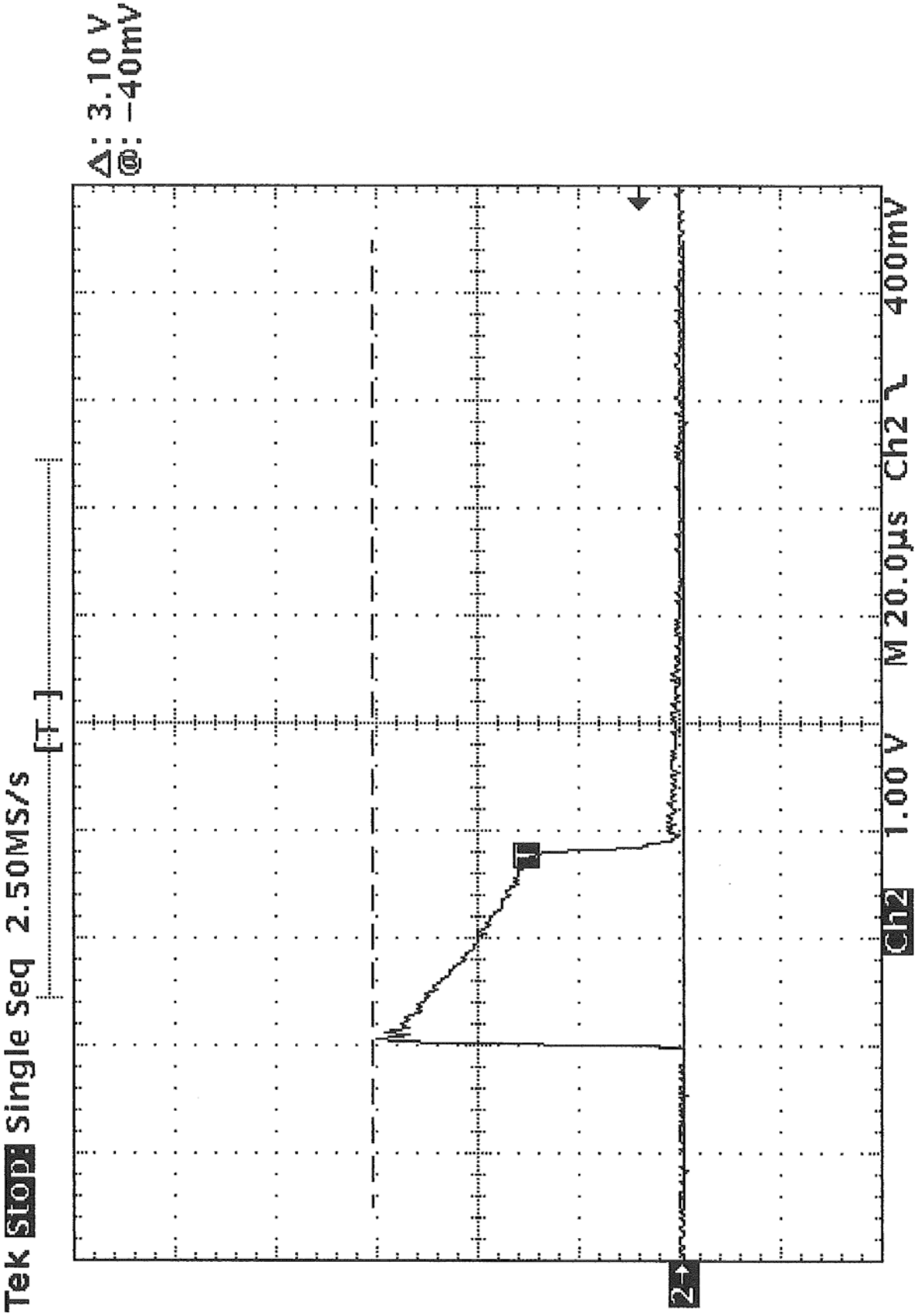
**Test Voltage: -6kV (Device Parallel)**



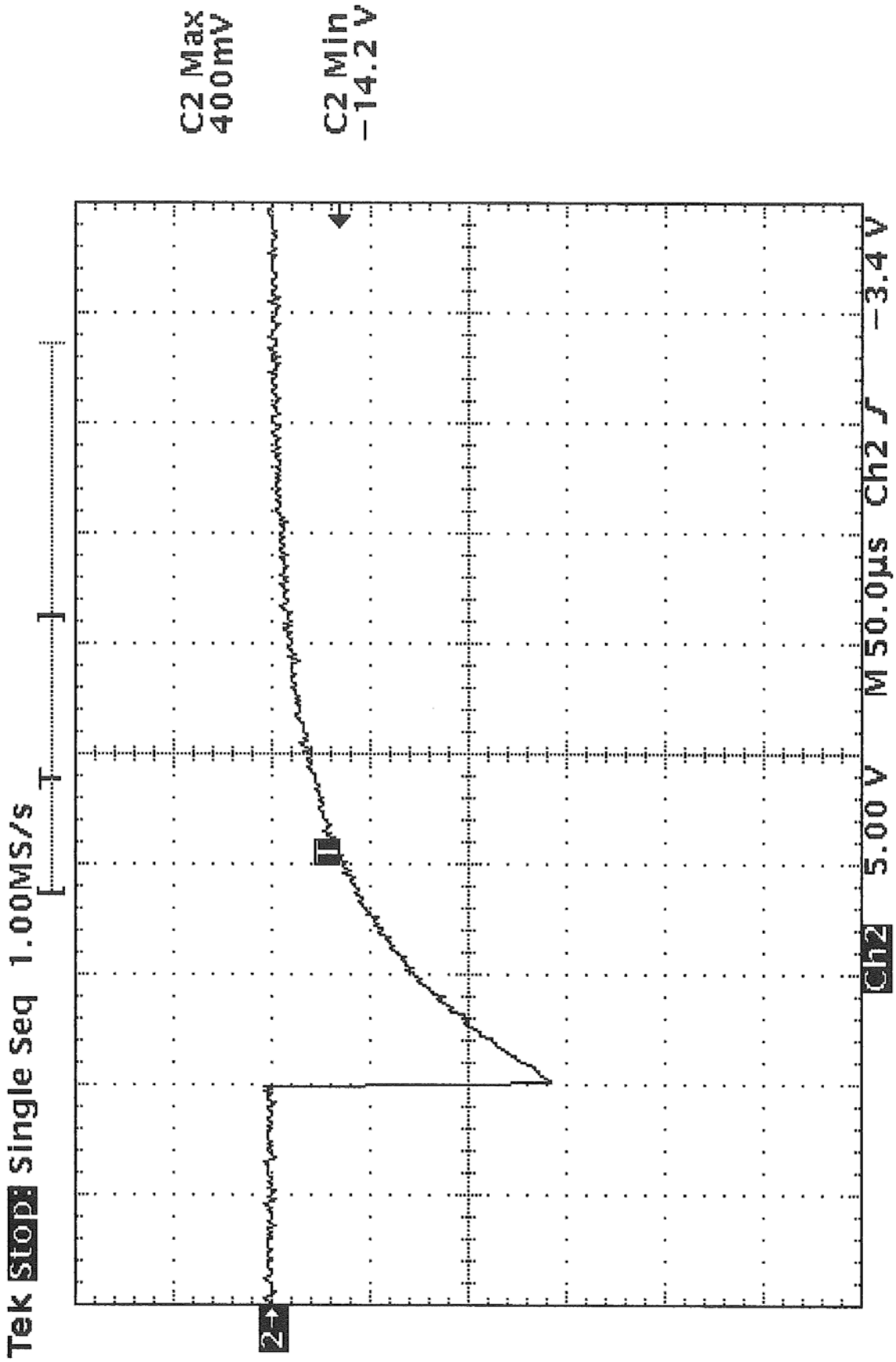
**Test Voltage: +15.0 kV Waveform (Normal)**



**Test Voltage: +15.0 kV (Device Parallel)**



**Test Voltage: -15.0 kV Waveform (Normal)**



**Test Voltage: -15.0 kV (Device Parallel)**